7. Package Related Reliability Test Data

Pre-condition Test

1. Test Condition

   Step 1: TCT (-65°C/150°C, 5 cycles)
   Step 2: Bake (125°C, 24 hours)
   Step 3: Soak (60°C/60%RH, 52 hours)
   Step 4: IR, 3 passes

2. DRAM Products

<table>
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<tr>
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<th>No. of Fails</th>
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3. Non-Volatile Memory Products

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Temperature Cycle Test (TCT)

1. Test Condition
   
   Condition: T = -65°C ~ +150 °C, condition C, soak mode 1
   Duration: 500 cycles

2. DRAM Products

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Pressure Cooker Test (PCT) / Un-biased Highly Accelerated Stress Test (uHAST)

1. Test Condition

Condition:  
T = 121°C, RH = 100%, Non-bias for PCT  
T = 130°C, RH = 85%, Non-bias for uHAST

Duration: 96 hrs

2. DRAM Products

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Highly Accelerated Stress Test (HAST)

1. Test Condition

Condition:  
- T = 130°C/96hrs for TSOP/SOP
- T = 110°C/264hrs for BGA
- RH = 85%
- Bias = Vddmax

Duration:  
- 96hrs, 168hrs, 264hrs

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